

April 1992 Revised May 2005

# 74ABT162244 16-Bit Buffer/Line Driver with 25Ω Series Resistors in the Outputs

#### **General Description**

The ABT162244 contains sixteen non-inverting buffers with 3-STATE outputs designed to be employed as a memory and address driver, clock driver, or bus oriented transmitter/receiver. The device is nibble controlled. Individual 3-STATE control inputs can be shorted together for 8-bit or 16-bit operation.

The  $25\Omega$  series resistors in the outputs reduce ringing and eliminate the need for external resistors.

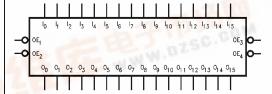
#### **Features**

- Separate control logic for each nibble
- 16-bit version of the ABT2244
- Guaranteed latchup protection
- High impedance glitch free bus loading during entire power up and power down cycle
- Non-destructive hot insertion capability

# **Ordering Code:**

Order Number	Package Number	Package Description
74ABT162244CSSC	MS48A	48-Lead Small Shrink Outline Package (SSOP), JEDEC MO-118, 0.300" Wide [RAIL]
74ABT162244CSSX	MS48A	48-Lead Small Shrink Outline Package (SSOP), JEDEC MO-118, 0.300" Wide [TAPE and REEL]
74ABT162244CMTD	MTD48	48-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 6.1mm Wide [RAIL]
74ABT162244MTDX	MTD48	48-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 6.1mm Wide [TAPE and REEL]

#### **Logic Symbol**



#### **Pin Descriptions**

Pin Names	Description
<del>OE</del> <sub>n</sub>	Output Enable Input (Active LOW)
I <sub>0</sub> –I <sub>15</sub>	Inputs
O <sub>0</sub> -O <sub>15</sub>	Outputs

#### **Connection Diagram**





# **Truth Tables**

In	Inputs		
OE <sub>1</sub>	I <sub>0</sub> -I <sub>3</sub>	O <sub>0</sub> -O <sub>3</sub>	
L	L	L	
L	Н	Н	
Н	Χ	Z	

In	Inputs		
ŌE <sub>3</sub>	I <sub>8</sub> −I <sub>11</sub>	O <sub>8</sub> -O <sub>11</sub>	
L	L	L	
L	Н	Н	
н	X	Z	

In	Inputs		
OE <sub>2</sub>	I <sub>4</sub> –I <sub>7</sub>	04-07	
L	L	L	
L	Н	н	
Н	X	Z	

In	Inputs		
OE <sub>4</sub> I <sub>12</sub> -I <sub>15</sub>		O <sub>12</sub> -O <sub>15</sub>	
L	L	L	
L	Н	Н	
Н	X	Z	

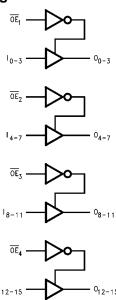
- H = HIGH Voltage Level L = LOW Voltage Level

- X = Immaterial Z = High Impedance

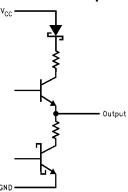
# **Functional Description**

The ABT162244 contains sixteen non-inverting buffers with 3-STATE outputs. The device is nibble (4 bits) controlled with each nibble functioning identically, but independent of the other. The control pins can be shorted together to obtain full 16-bit operation.

# **Logic Diagram**



# **Schematic of each Output**



# **Absolute Maximum Ratings**(Note 1)

# Recommended Operating Conditions

 $\begin{array}{ll} \mbox{Storage Temperature} & -65\mbox{\,}^{\circ}\mbox{C to } +150\mbox{\,}^{\circ}\mbox{C} \\ \mbox{Ambient Temperature under Bias} & -55\mbox{\,}^{\circ}\mbox{C to } +125\mbox{\,}^{\circ}\mbox{C} \\ \end{array}$ 

Junction Temperature under Bias -55°C to +150°C

V<sub>CC</sub> Pin Potential to Ground Pin -0.5V to +7.0V

Input Voltage (Note 2) -0.5V to +7.0V Input Current (Note 2) -30 mA to +5.0 mA

Voltage Applied to Any Output

in the Disabled or

Power-Off State -0.5V to 5.5V in the HIGH State -0.5V to  $V_{CC}$ 

Current Applied to Output

in LOW State (Max)  ${\rm twice \ the \ rated \ I_{OL} \ (mA)}$  DC Latchup Source Current  ${\rm -500 \ mA}$ 

Over Voltage Latchup (I/O) 10V

Free Air Ambient Temperature  $-40^{\circ}\text{C}$  to  $+85^{\circ}\text{C}$ Supply Voltage +4.5V to +5.5V

Minimum Input Edge Rate (ΔV/Δt)

Data Input 50 mV/ns
Enable Input 20 mV/ns

**Note 1:** Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

### **DC Electrical Characteristics**

Symbol	Parameter	Min	Тур	Max	Units	V <sub>CC</sub>	Conditions
V <sub>IH</sub>	Input HIGH Voltage	2.0			V		Recognized HIGH Signal
$V_{IL}$	Input LOW Voltage			0.8	V		Recognized LOW Signal
$V_{CD}$	Input Clamp Diode Voltage			-1.2	V	Min	I <sub>IN</sub> = -18 mA
V <sub>OH</sub>	Output HIGH Voltage	2.5			V	Min	I <sub>OH</sub> = -3 mA
		2.0			V	Min	I <sub>OH</sub> = -32 mA
V <sub>OL</sub>	Output LOW Voltage			0.8	V	Min	I <sub>OL</sub> = 12 mA
I <sub>IH</sub>	Input HIGH Current			1	μА	Max	V <sub>IN</sub> = 2.7V (Note 3)
				1	μΛ	IVIAX	$V_{IN} = V_{CC}$
I <sub>BVI</sub>	Input HIGH Current Breakdown Test			7	μА	Max	V <sub>IN</sub> = 7.0V
I <sub>IL</sub>	Input LOW Current			-1	μА	Max	V <sub>IN</sub> = 0.5V (Note 3)
				-1	μΛ	IVIAX	$V_{IN} = 0.0V$
$V_{ID}$	Input Leakage Test	4.75			V	0.0	I <sub>ID</sub> = 1.9 μA
							All Other Pins Grounded
I <sub>OZH</sub>	Output Leakage Current			10	μА	0 – 5.5V	$V_{OUT} = 2.7V; \overline{OE}_n = 2.0V$
I <sub>OZL</sub>	Output Leakage Current			-10	μА	0 – 5.5V	$V_{OUT} = 0.5V; \overline{OE}_n = 2.0V$
Ios	Output Short-Circuit Current	-100		-275	mA	Max	V <sub>OUT</sub> = 0.0V
I <sub>CEX</sub>	Output High Leakage Current			50	μА	Max	V <sub>OUT</sub> = V <sub>CC</sub>
$I_{ZZ}$	Bus Drainage Test			100	μА	0.0	V <sub>OUT</sub> = 5.5V; All Others GND
I <sub>CCH</sub>	Power Supply Current			2.0	mA	Max	All Outputs HIGH
I <sub>CCL</sub>	Power Supply Current			60	mA	Max	All Outputs LOW
I <sub>CCZ</sub>	Power Supply Current			2.0	mA	Max	OE <sub>n</sub> = V <sub>CC</sub>
							All Others at V <sub>CC</sub> or GND
I <sub>CCT</sub>	Additional I <sub>CC</sub> /Input Outputs Enabled			3.0	mA		$V_I = V_{CC} - 2.1V$
	Outputs 3-STATE			3.0	mA	Max	Enable Input V <sub>I</sub> = V <sub>CC</sub> - 2.1V
	Outputs 3-STATE			50	μА		Data Input V <sub>I</sub> = V <sub>CC</sub> - 2.1V
							All Others at V <sub>CC</sub> or GND
I <sub>CCD</sub>	Dynamic I <sub>CC</sub> No Load				mA/	Max	Outputs OPEN
	(Note 3)			0.1	MHz	iviax	$\overline{OE}_n = GND$
							One Bit Toggling, 50% Duty Cycle

Note 3: Guaranteed, but not tested.

# **AC Electrical Characteristics**

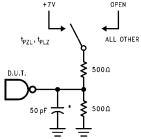
Symbol	Parameter		$T_A = +25^{\circ}C$ $V_{CC} = +5V$ $C_L = 50 \text{ pF}$		V <sub>CC</sub> = 4.	C to +85°C .5V–5.5V 50 pF	Units
		Min	Тур	Max	Min	Max	
t <sub>PLH</sub>	Propagation	1.0	2.4	3.9	1.0	3.9	ns
t <sub>PHL</sub>	Delay Data to Outputs	1.0	3.2	4.7	1.0	4.7	115
t <sub>PZH</sub>	Output	1.5	3.5	6.3	1.5	6.3	ns
$t_{PZL}$	Enable Time	1.5	4.2	6.9	1.5	6.9	115
t <sub>PHZ</sub>	Output	1.0	4.2	6.7	1.0	6.7	ns
$t_{PLZ}$	Disable Time	1.0	3.8	6.7	1.0	6.7	115

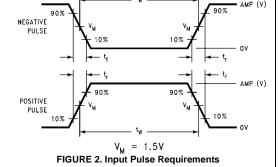
# Capacitance

Symbol	Parameter	Тур	Units	Conditions T <sub>A</sub> = 25°C
C <sub>IN</sub>	Input Capacitance	5.0	pF	V <sub>CC</sub> = 0.0V
C <sub>OUT</sub> (Note 4)	Output Capacitance	9.0	pF	V <sub>CC</sub> = 5.0V

Note 4: C<sub>OUT</sub> is measured at frequency f = 1 MHz per MIL-STD-883, Method 3012.

# **AC Loading**





\*Includes jig and probe capacitance

FIGURE 1. Standard AC Test Load

Amplitude	Rep. Rate	t <sub>W</sub>	t <sub>r</sub>	t <sub>f</sub>
3.0V	1 MHz	500 ns	2.5 ns	2.5 ns

FIGURE 3. Test Input Signal Requirements

#### **AC Waveforms**

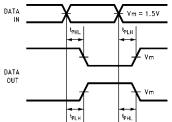


FIGURE 4. Propagation Delay Waveforms for Inverting and Non-Inverting Functions

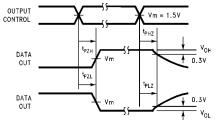


FIGURE 6. 3-STATE Output HIGH and LOW Enable and Disable Times

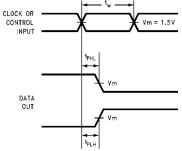


FIGURE 5. Propagation Delay, Pulse Width Waveforms

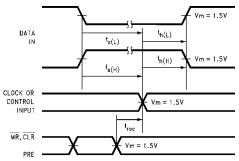
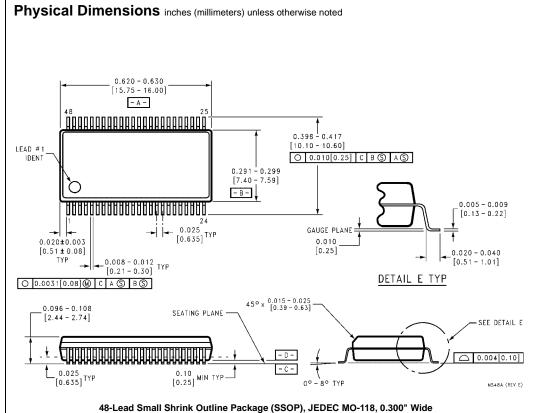
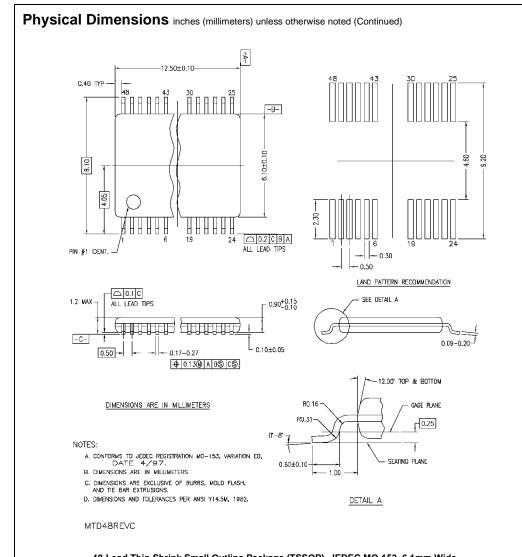


FIGURE 7. Setup Time, Hold Time and Recovery Time Waveforms



48-Lead Small Shrink Outline Package (SSOP), JEDEC MO-118, 0.300" Wide Package Number MS48A



48-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 6.1mm Wide Package Number MTD48

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